Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
09/900,842	FREED, ERIK J.	
Examiner	Art Unit	

2194

VAN H. NGUYEN

SEARCHED				
Class	Subclass	Date	Examiner	
719	310,317	8/27/2005	VN	
709	202	8/27/2005	VN	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
		-		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
INVENTOR NAME SEARCH	8/27/2005	VN	
WEST (SEE SEARCH HISTORY PRINTOUT	8/27/2005	VN	
IEEE (SEE SEARCH HISTORY PRINTOUT)	8/27/2005	VN	
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